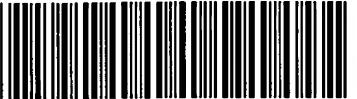


<b>Search Notes</b> 				<b>Application/Control No.</b> 10/666,462 <b>Examiner</b> Hae M. Hyeon		<b>Applicant(s)/Patent under Reexamination</b> STONE ET AL. <b>Art Unit</b> 2839	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>			
Class	Subclass	Date	Examiner			DATE	EXMR
Search	Updated	6/06	hah				
<b>INTERFERENCE SEARCHED</b>							
Class	Subclass	Date	Examiner				